

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10573166	TANAKA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Sheela J Huff	1643

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
inventor serach on PALNM	10/21/08	sjh
SCORE- SEQ ID NO. 2 and 3	10/21/08	sjh
Stic structure search	10/21/08	sjh
WEST-insert	10/21/08	sjh
STN-inseret	10/21/08	sjh
WEST-insert	4/7/09	sjh
EAST-insert	9/14/09	sjh

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
EAST- uspgpub		9/14/09	sjh

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